Notice of References Cited Application/Control No. 10/563,501 Examiner Sin J. Lee Applicant(s)/Patent Under Reexamination HADA ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν	JP2003-233187	08-2003	Japan	Sato	N/A
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NON-PATENT DOCUMENTS

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	U	Machine-assisted English translation of JP 2003-233187 as provided by JPO.		
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